



XTR2N0807

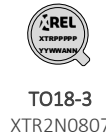
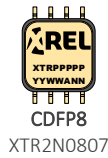
High Temperature 80V N-Channel Small Signal MOSFET

Rev 3 – August 2021 (DS-00418-13)

Data Sheet



PRODUCTION



FEATURES

- Minimum $BV_{DSS} = 90V$.
- Allowed V_{GS} range $-5.5V$ to $+5.5V$.
- Operational beyond the $-60^{\circ}C$ to $+230^{\circ}C$ temperature range.
- Low $R_{DS(on)}$
 - XTR2N0807: 9.5Ω @ $230^{\circ}C$
- Maximum I_D :
 - XTR2N0807: $600mA$ @ $230^{\circ}C$
- On-time ($t_{d(on)}+t_r$):
 - XTR2N0807: $12nsec$ @ $230^{\circ}C$
- Off-time ($t_{d(off)}+t_f$):
 - XTR2N0807: $33nsec$ @ $230^{\circ}C$
- Available in ruggedized SMT and thru-hole packages.
- Parts are also available as bare dies.

APPLICATIONS

- Reliability-critical, Automotive, Aeronautics & Aerospace, Down-hole.
- Linear regulators, switching applications, sensor driving, level shifting.

DESCRIPTION

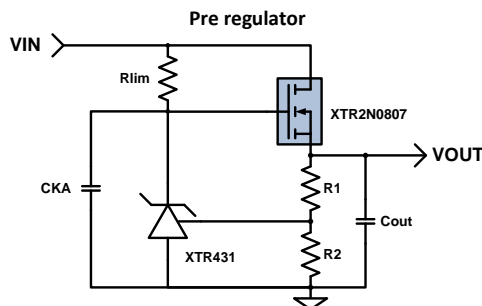
XTR2N0807 is an N-channel small signal MOSFETs designed to reliably operate over a wide range of temperatures. Full functionality is guaranteed from $-60^{\circ}C$ to $+230^{\circ}C$, though operation well below and above this temperature range is achieved.

Fabricated on a Silicon-on-Insulator (SOI) process, XTR2N0807 family parts offer reduced leakage currents while providing high drain currents and low $R_{DS(on)}$. These features allow XTR2N0807 parts to be ideally suited for switching applications.

XTR2N0807 family parts have been designed to reduce system cost and ease adoption by reducing the learning curve and providing smart and easy to use features.

XTR2N0807 parts are available ruggedized SMT and thru-hole packages. Parts are also available as bare dies.

PRODUCT HIGHLIGHT



ORDERING INFORMATION

X
↓
Source :
X = X-REL Semi

TR
↓
Process:
TR = HiTemp, HiRel

2N
↓
Part family

0807
↓
Part number

Product Reference	Temperature Range	Package	Pin Count	Marking
XTR2N0807-TD	$-60^{\circ}C$ to $+230^{\circ}C$	Tested bare die		
XTR2N0807-FE	$-60^{\circ}C$ to $+230^{\circ}C$	Gull-wing flat pack with ePad	8	XTR2N0807
XTR2N0807-T	$-60^{\circ}C$ to $+230^{\circ}C$	TO-18 metal can	3	XTR2N0807

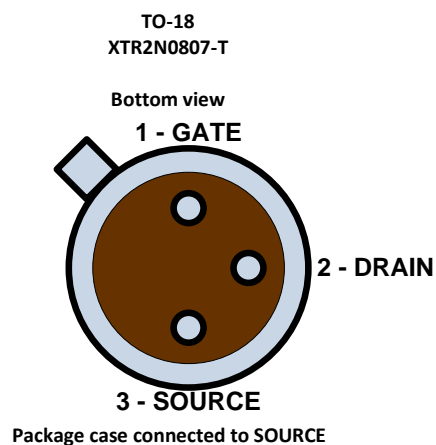
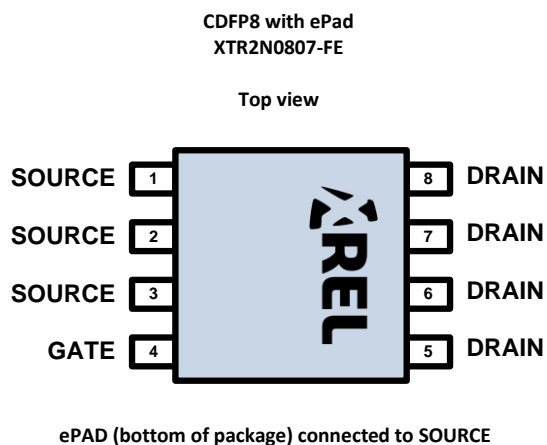
Other packages and packaging configurations possible upon request. For some packages or packaging configurations, MOQ may apply.

ABSOLUTE MAXIMUM RATINGS

Drain-source voltage	-2V to +90V
Gate-source voltage	±6.0V
Storage temperature range	-70°C to +230°C
Operating junction temperature range	-70°C to +300°C
ESD classification	1kV HBM MIL-STD-750

Caution: Stresses beyond those listed in “ABSOLUTE MAXIMUM RATINGS” may cause permanent damage to the device. These are stress ratings only and functionality of the device at these or any other condition beyond those indicated in the operational sections of the specifications is not implied. Exposure to “ABSOLUTE MAXIMUM RATINGS” conditions for extended periods may permanently affect device reliability.

PRODUCT VARIANTS



THERMAL CHARACTERISTICS

Parameter	Condition	Min	Typ	Max	Units
XTR2N0807-FE (DFP8)					
Thermal Resistance: J-C $R_{Th_{J-C}}$	Resistance to exposed pad.		15		°C/W
Thermal Resistance: J-A $R_{Th_{J-A}}$			85		°C/W
XTR2N0807-T (TO-18)					
Thermal Resistance: J-C $R_{Th_{J-C}}$			55		°C/W
Thermal Resistance: J-A $R_{Th_{J-A}}$			300		°C/W

RECOMMENDED OPERATING CONDITIONS

Parameter	Min	Typ	Max	Units
Drain-source voltage V_{DS}	-1.5		80	V
Gate-source voltage V_{GS}	-5.5		+5.5	V
Junction Temperature ¹ T_J	-60		230	°C

¹ Operation beyond the specified temperature range is achieved. The -60°C to +230°C range for the case temperature is considered for the case where $I_D \leq I_{D(DC)}$ for a given case temperature.

XTR2N0807 SPECIFICATIONS

Unless otherwise stated, specification applies for -60°C < T_J < 230°C.

Parameter	Condition	Min	Typ	Max	Units
DC Characteristics					
Drain-source breakdown voltage BV_{DSS}	$V_{GS}=0V, I_{DS}=100\mu A, T_J=25^\circ C$	90			V
Static drain-source on-state resistance $R_{DS(on)}$	$V_{GS}=+5V, V_{DS}=50mV$ $T_C=-60^\circ C$ $T_C=85^\circ C$ $T_C=230^\circ C$		3.5 6.1 9.5	4.6 8.0 12.4	Ω
Continuous drain current $I_{D(DC)}$	$V_{GS}=+5V$ for T0-18 $T_J=-60^\circ C$ $T_J=85^\circ C$ $T_J=230^\circ C$	190 140 105	270 200 150		mA
Gate threshold voltage $V_{GS(th)}$	$V_{DS}=V_{GS}, I_{DS}=1mA$ $T_C=-60^\circ C$ $T_C=85^\circ C$ $T_C=230^\circ$		1.84 1.53 1.18		V
Temperature drift of gate threshold voltage $\Delta V_{GS(th)}/\Delta T_J$	$V_{DS}=V_{GS}, I_{DS}=1mA$		-2.27		mV/°C
Off-state drain current I_{DSS}	$V_{DS}=80V, V_{GS}=0V$ $T_C=85^\circ C$ $T_C=230^\circ C$		0.004 2.0	0.03 10	μA
Gate Leakage current I_{GSS}	$V_{GS}=\pm 5V, V_{DS}=0V$ $T_C=85^\circ C$ $T_C=230^\circ C$		± 0.9 ± 100	± 5 ± 700	nA
AC Characteristics					
Input capacitance C_{iss}	$V_{DS}=40V, V_{GS}=0V, f=1MHz$		38		pF
Output capacitance C_{oss}			8.3		pF
Reverse transfer capacitance C_{rss}			1.5		pF
Switching Characteristics					
Pulsed drain current I_{DM}	$V_{DS}=40V, V_{GS sweep}=0$ to +5V, $d=0.2\%, \tau=1ms$ $T_C=-60^\circ C$ $T_C=85^\circ C$ $T_C=230^\circ C$	770 560 420	1110 800 600		mA
Total gate charge Q_g	$V_{DS}=40V, V_{GS sweep}=0$ to +5V		0.62		nC
Turn-on delay time $t_{d(on)}$	$V_{DS}=20V, V_{GS sweep}=0$ to +5V, $R_D=100\Omega, d=0.2\%, \tau=1ms$		7.2		ns
Rise time t_r	$V_{DS}=20V, V_{GS sweep}=0$ to +5V, $R_D=100\Omega, d=0.2\%, \tau=1ms$		4.7		
Turn-off delay time $t_{d(off)}$	$V_{DS}=20V, V_{GS sweep}=0$ to +5V, $R_D=100\Omega, d=0.2\%, \tau=1ms$		10.3		
Fall time t_f	$V_{DS}=20V, V_{GS sweep}=0$ to +5V, $R_D=100\Omega, d=0.2\%, \tau=1ms$		22		
Drain-Source Diode Characteristics					
Forward diode voltage $V_{SD_{100mA}}$	$V_{GS}=0V, I_{DS}=-100mA$ $T_C=-60^\circ C$ $T_C=85^\circ C$ $T_C=230^\circ C$		1.16 1.05 0.95		V

TYPICAL PERFORMANCE

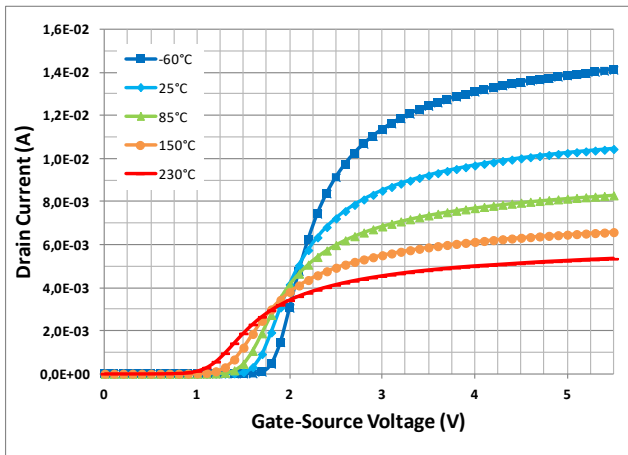


Figure 1. Drain Current (I_{DS}) vs Gate-Source Voltage for several case temperatures. $V_{DS}=50mV$.

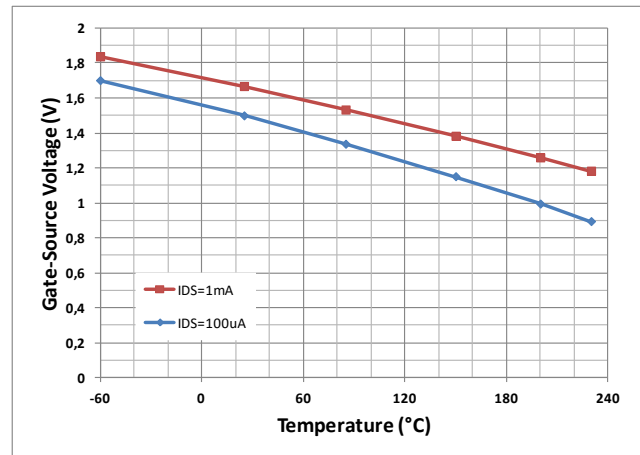


Figure 2. Gate-Source Threshold Voltage ($V_{GS(th)}$) vs Case temperatures. $V_{GS}=V_{DS}$.

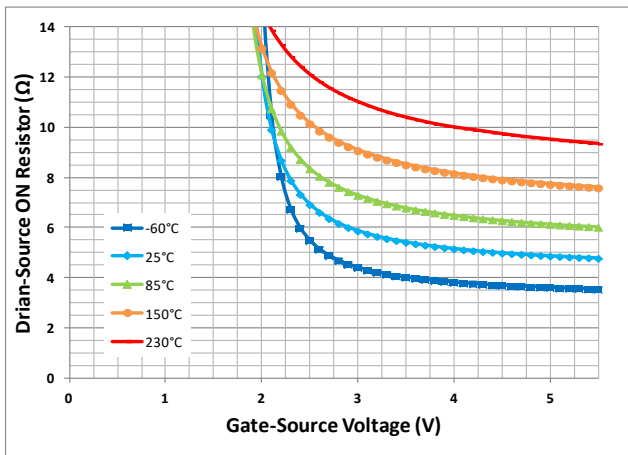


Figure 3. Drain-Source ON Resistance ($R_{DS(on)}$) vs Gate-Source Voltage for several case temperatures. $V_{DS}=50mV$.

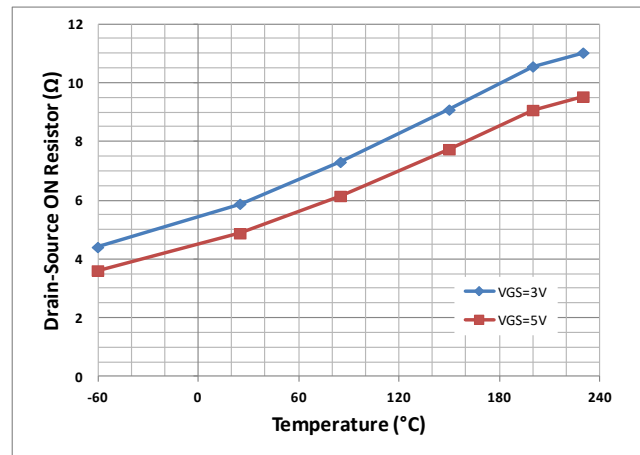


Figure 4. Drain-Source ON Resistance ($R_{DS(on)}$) vs Case Temperature. $V_{DS}=50mV$.

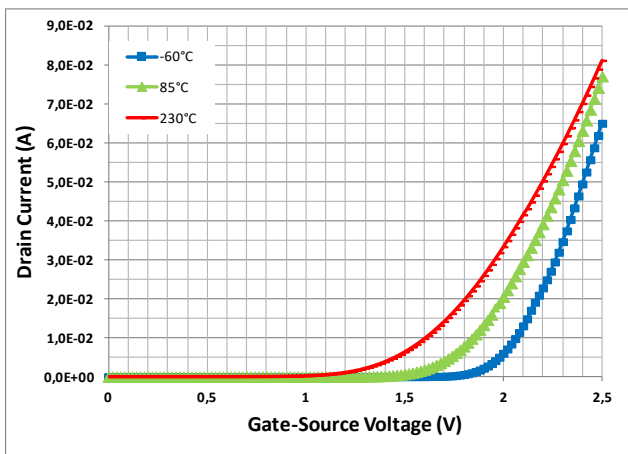


Figure 5. Drain Current (I_{DS}) vs Gate-Source Voltage for several case temperatures. $V_{GS}=V_{DS}$

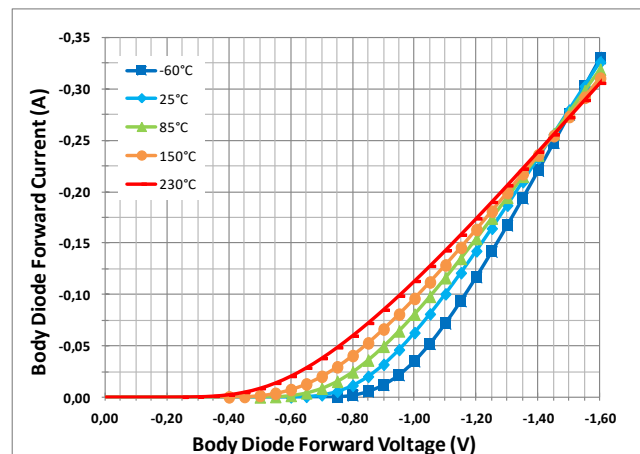


Figure 6. Body Diode Forward Current (I_{FD}) vs Forward Voltage for several case temperature. $V_{GS}=0V$.

TYPICAL PERFORMANCE (CONTINUED)

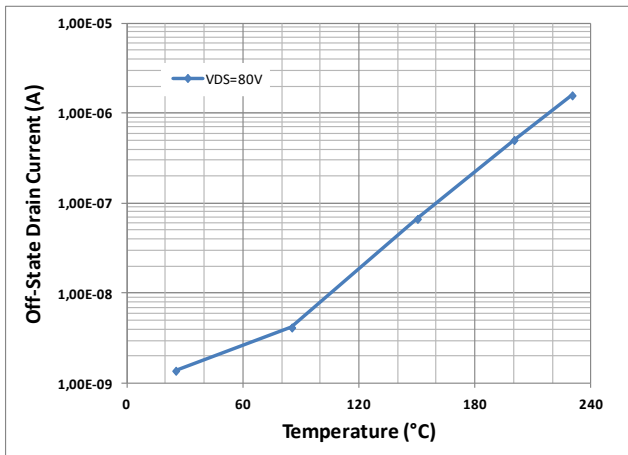


Figure 7. Off-State Drain Current (I_{DSS}) vs Case Temperature. $V_{DS}=80V$, $V_{GS}=0V$.

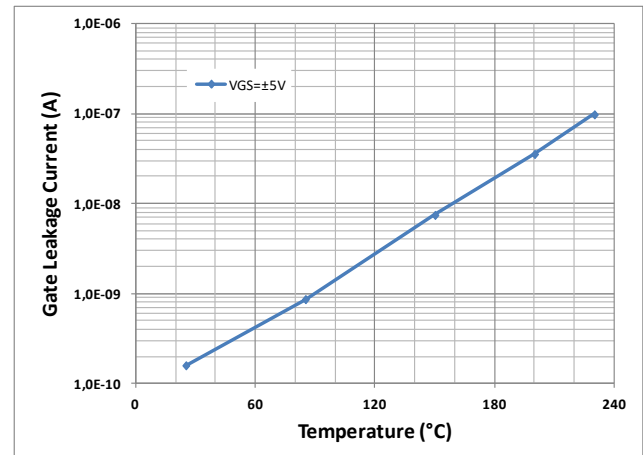


Figure 8. Gate Leakage Current (I_{GSS}) vs Case Temperature. $V_{GS}=\pm 5V$, $V_{DS}=0V$.

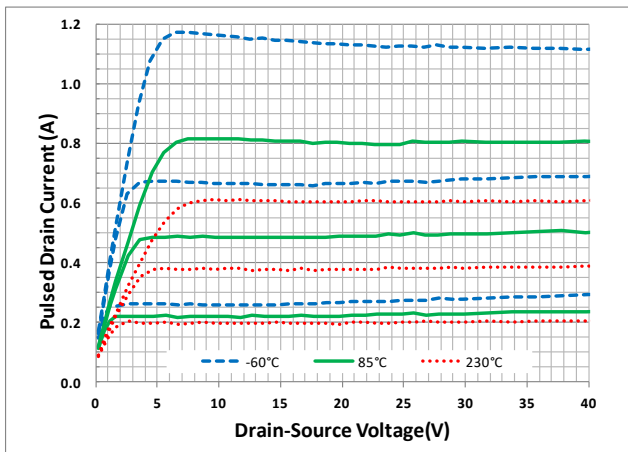


Figure 9. Pulsed Drain Current (I_{DM}) vs Drain-Source Voltage for several case temperatures. $V_{GS}=3V, 4V$ and $5V$.

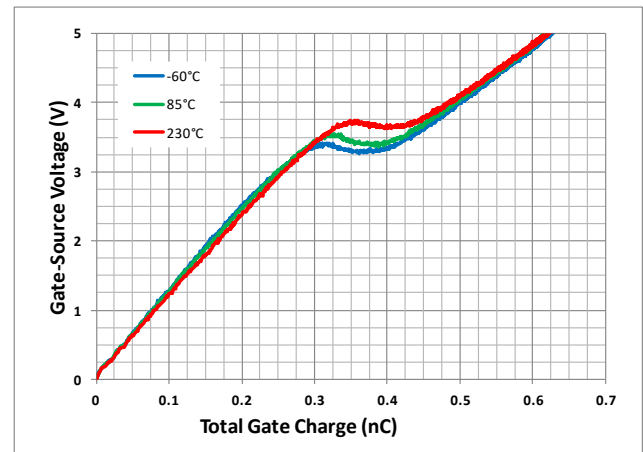


Figure 10. Total Gate Charge (Q_g) vs Gate-Source Voltage for several case temperatures. $I_{DS}=200mA$.

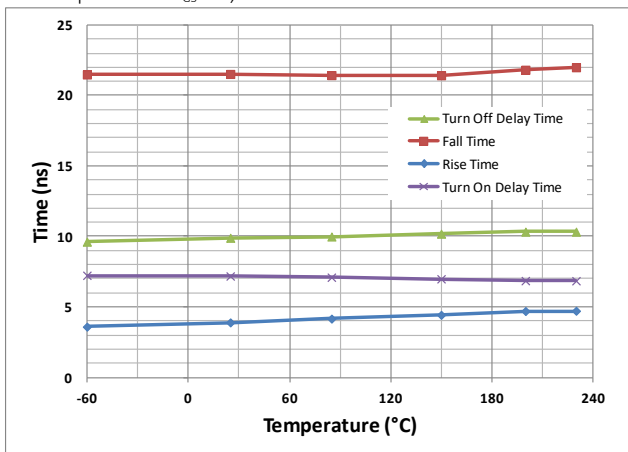


Figure 11. Timing Characteristics vs Case Temperature. $V_{DS}=20V$, V_{GS} sweep=0 to 5V.

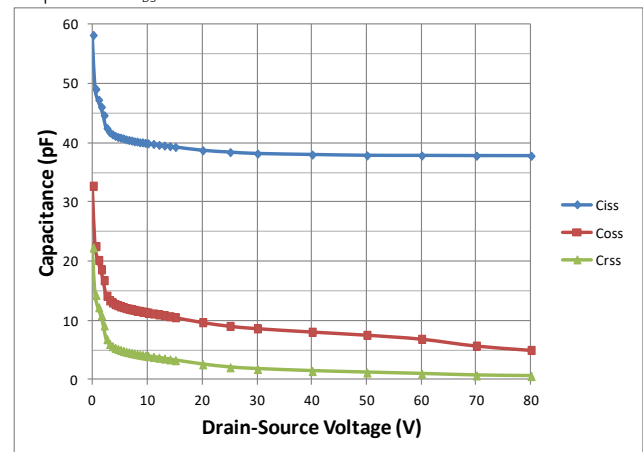


Figure 12. Capacitance vs Drain-Source Voltage at $T_c=25^\circ C$.

PARAMETER DEFINITION

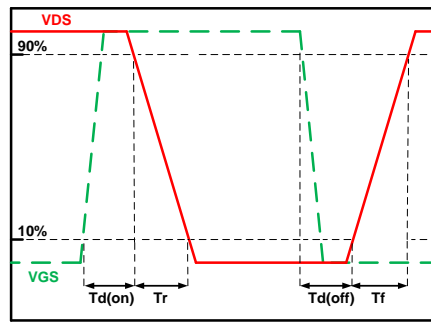
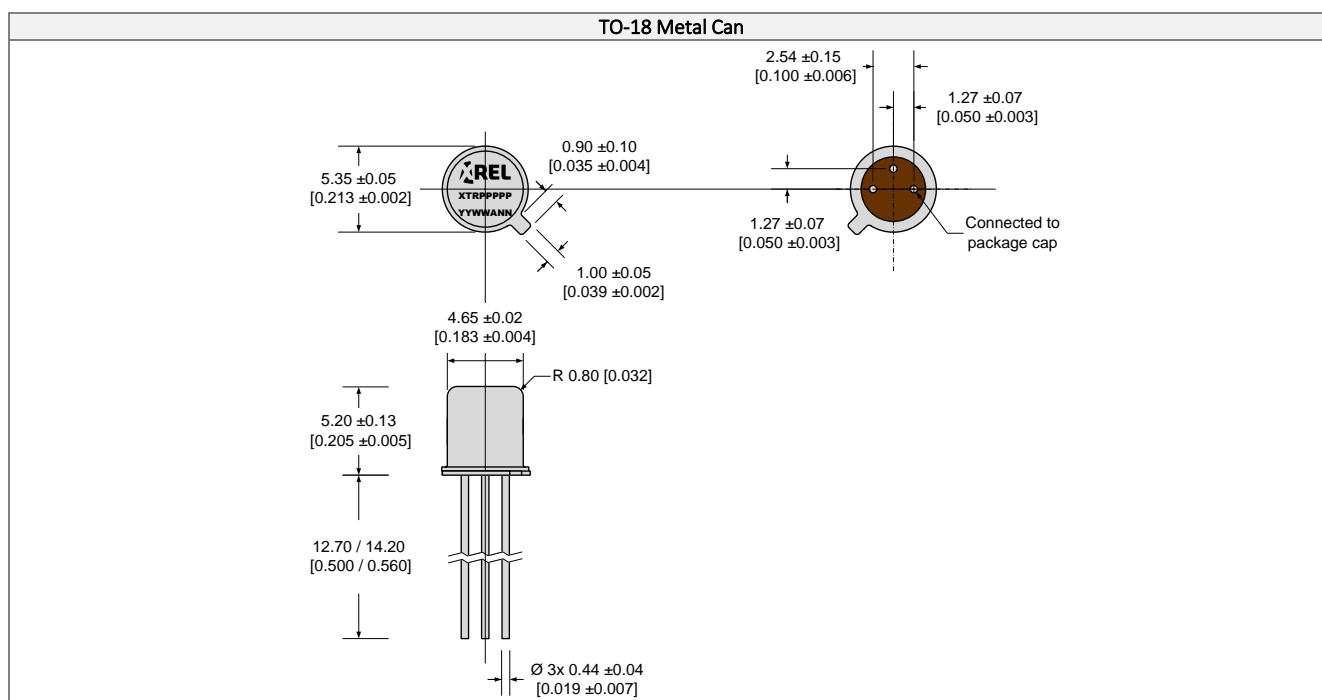
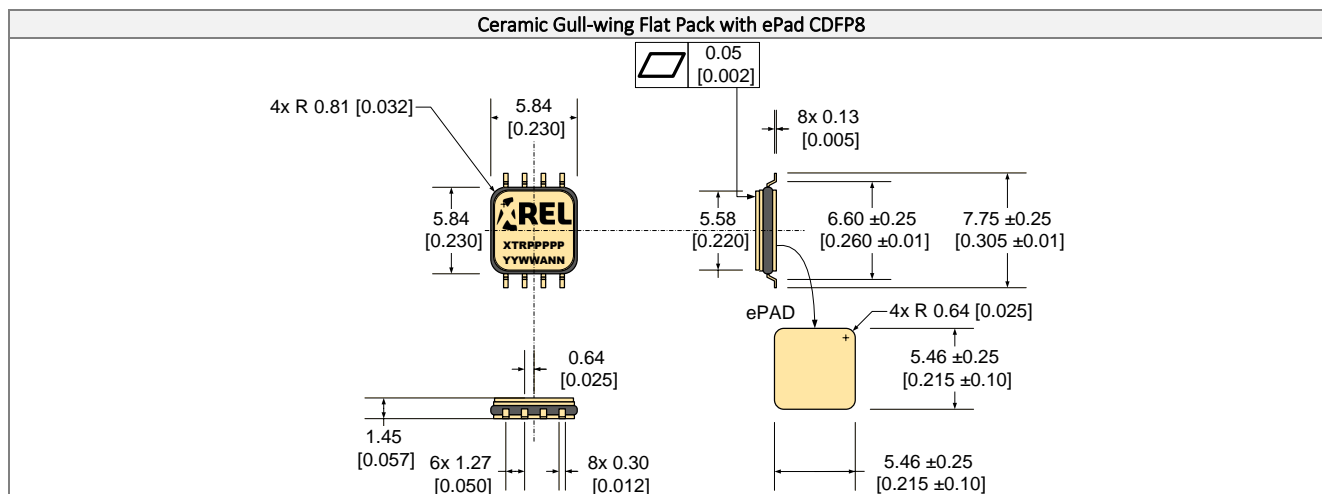


Figure 13. Timing diagram definition.

PACKAGE OUTLINES

Dimensions shown in mm [inches]. Tolerances ± 0.13 mm [± 0.005 in] unless otherwise stated.



Part Marking Convention

Part Reference: XTRPPPPP

XTR	X-REL Semiconductor, high-temperature, high-reliability product (XTRM Series).
PPPPP	Part number (0-9, A-Z).

Unique Lot Assembly Code: YYWWANN

YY	Two last digits of assembly year (e.g. 11 = 2011).
WW	Assembly week (01 to 52).
A	Assembly location code.
NN	Assembly lot code (01 to 99).

IMPORTANT NOTICE & DISCLAIMER

Information in this document supersedes and replaces all information previously supplied. Information in this document is provided solely in connection with EASii IC products from the X-REL business unit.

The information contained herein is believed to be reliable. EASii IC makes no warranties regarding the information contained herein. EASii IC assumes no responsibility or liability whatsoever for any of the information contained herein. EASii IC assumes no responsibility or liability whatsoever for the use of the information contained herein. The information contained herein is provided "AS IS, WHERE IS" and with all faults, and the entire risk associated with such information is entirely with the user. EASii IC reserves the right to make changes, corrections, modifications or improvements, to this document and the information herein without notice. Customers should obtain and verify the latest relevant information before placing orders for EASii IC products. The information contained herein or any use of such information does not grant, explicitly or implicitly, to any party any patent rights, licenses, or any other intellectual property rights, whether with regard to such information itself or anything described by such information.

Unless expressly approved in writing by an authorized representative of EASii IC, EASii IC products are not designed, authorized or warranted for use in military, aircraft, space, lifesaving, or life sustaining applications, nor in products or systems where failure or malfunction may result in personal injury, death, or property or environmental damage.

General Sales Terms & Conditions apply.

For product information and a complete list of distributors, please go to our web site: www.x-relsemi.com



90, Avenue Leon Blum 38100 Grenoble — France

☎ : +33 456 580 580

✉ : support.XREL@easii-ic.com

EASii IC, X-REL Semiconductor, and the logo are trademarks of EASii IC in France and other countries.
Data subject to change. Copyright © 2002-2021 EASii IC. All rights reserved.